

Intensity-dependent effects in the ILC BDS

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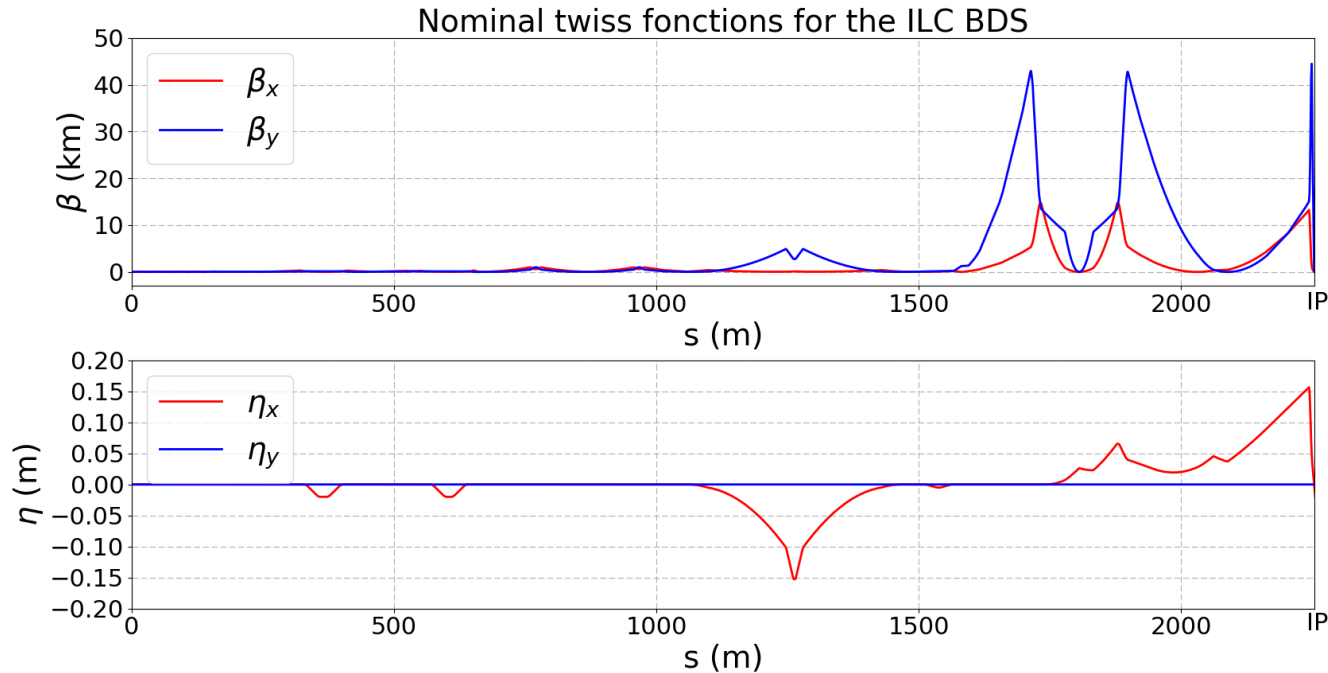


Outline

- **Presentation of resistive walls.**
- **Beam Based Alignment (BBA) + knobs studies in the ILC BDS.**
- **Intensity dependent effects in the BDS for a bunch train.**

Introduction

ILC BDS 250GeV beam energy



Centre-of-mass energy	E_{CM}	500	GeV
Number of bunches	n_b	1312	
Bunch population	N	2.0×10^{10}	
RMS bunch length	σ_z	0.3	mm
Beta functions at the entrance of the BDS	β_x/β_y	51.3/9.40	m
Emittances at the entrance of the BDS	ϵ_x/ϵ_y	10/0.04	μm
IP beta functions	β_x^*/β_y^*	21/0.4	mm
IP RMS beam sizes	σ_x^*/σ_y^*	655/5.7	nm

Resistive walls

Resistive walls wakefield

- Electrons going through the pipe interacts with the surrounding structure and generates a wake field.
- This wake field produces a transverse kick for the following particles inside the same bunch (short range) but also for the following bunches (long range).

The following model is used for the transverse wake function:

$$W(z) = \frac{c}{\pi b^3} \sqrt{\left(\frac{Z_0}{\sigma_r \pi z}\right)} L$$

With b the radius of the beam pipe, Z_0 the impedance of the vacuum, σ_r the conductivity of the pipe and L the length of the beam line element

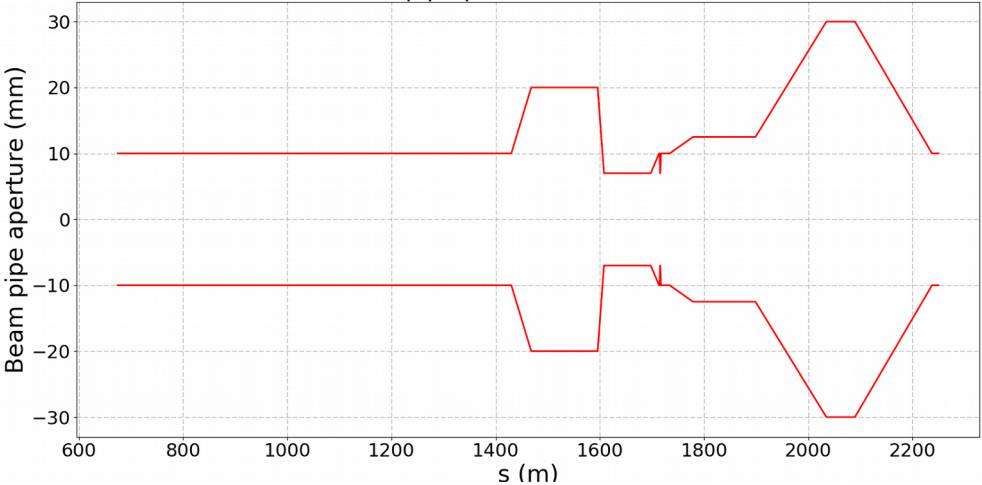
Resistive walls wakefield

$$W(z) = \frac{c}{4\pi b^3} \sqrt{\left(\frac{Z_0}{\tau z}\right) L}$$

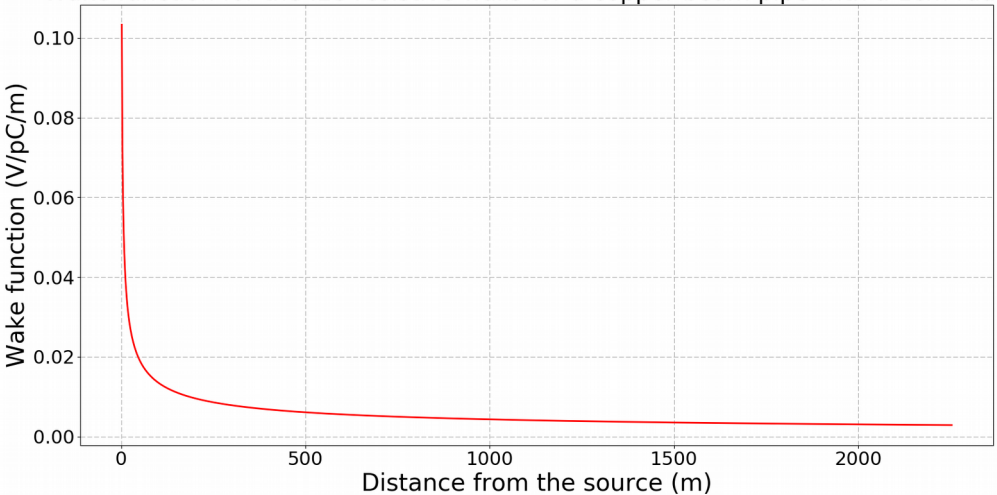
Beam pipe profile

Material used: copper

Beam pipe profile for the ILC BDS



Wake function for the ILC resistive walls for a copper beam pipe with a 1cm radius



Beam Based Alignment + knobs studies in the ILC BDS

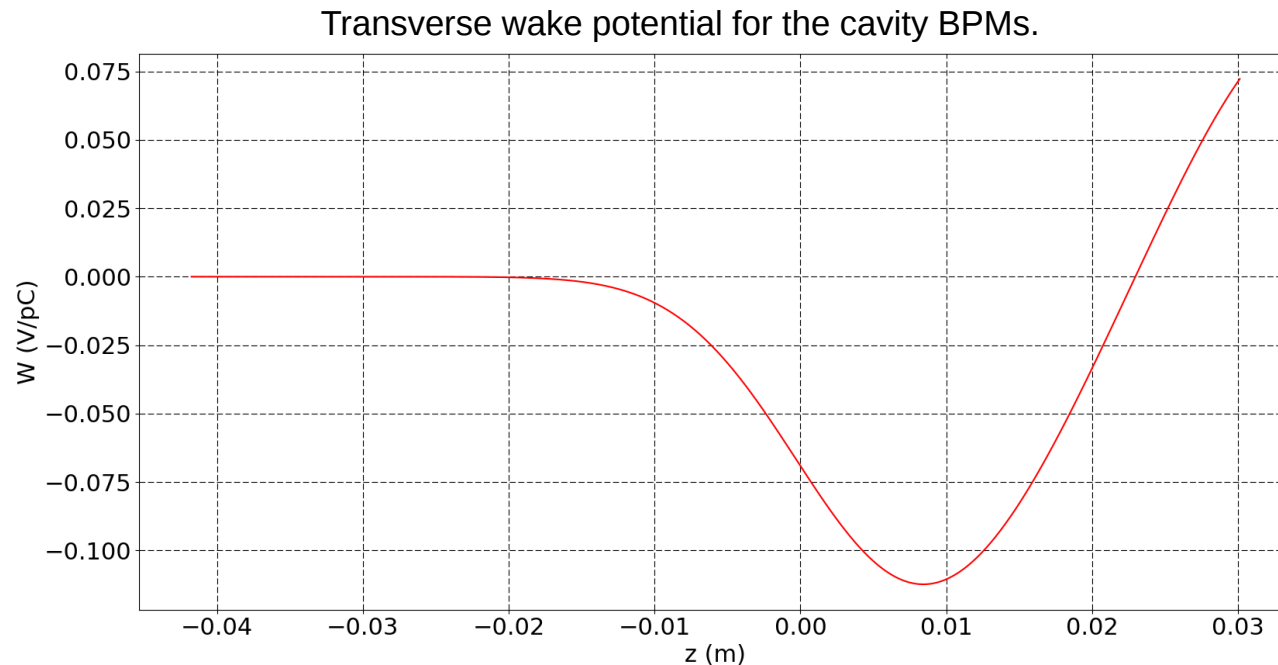
Simulation conditions for the BBA

- $N = 2.0 \times 10^{10}$ electrons.
- 100 random seeds (machines).
- BBA correction applied: 1to1, Dispersion Free Steering, Wakefield Free Steering. For DFS, $E = 2.5 \text{ GeV}$, for WFS, $q = 1e10$.
- Perfect knobs used to correct the IP distribution: $\langle y, x' \rangle$, $\langle y, y' \rangle$, $\langle y, E \rangle$, $\langle y, x'^2 \rangle$, $\langle y, x' * y' \rangle$, $\langle y, x' * E \rangle$.

The following errors:	Type of error	Amplitude
	Misalignment of quads, CBPMs and sextupoles	50 μm RMS
	BPM resolution	1.0 μm
	Roll errors	200 μrad RMS
	Strength error	1.0×10^{-4}

Simulation conditions for the BBA

- Wakefields used: Gdfdl simulations from A. Lyapin for cavity BPMs.

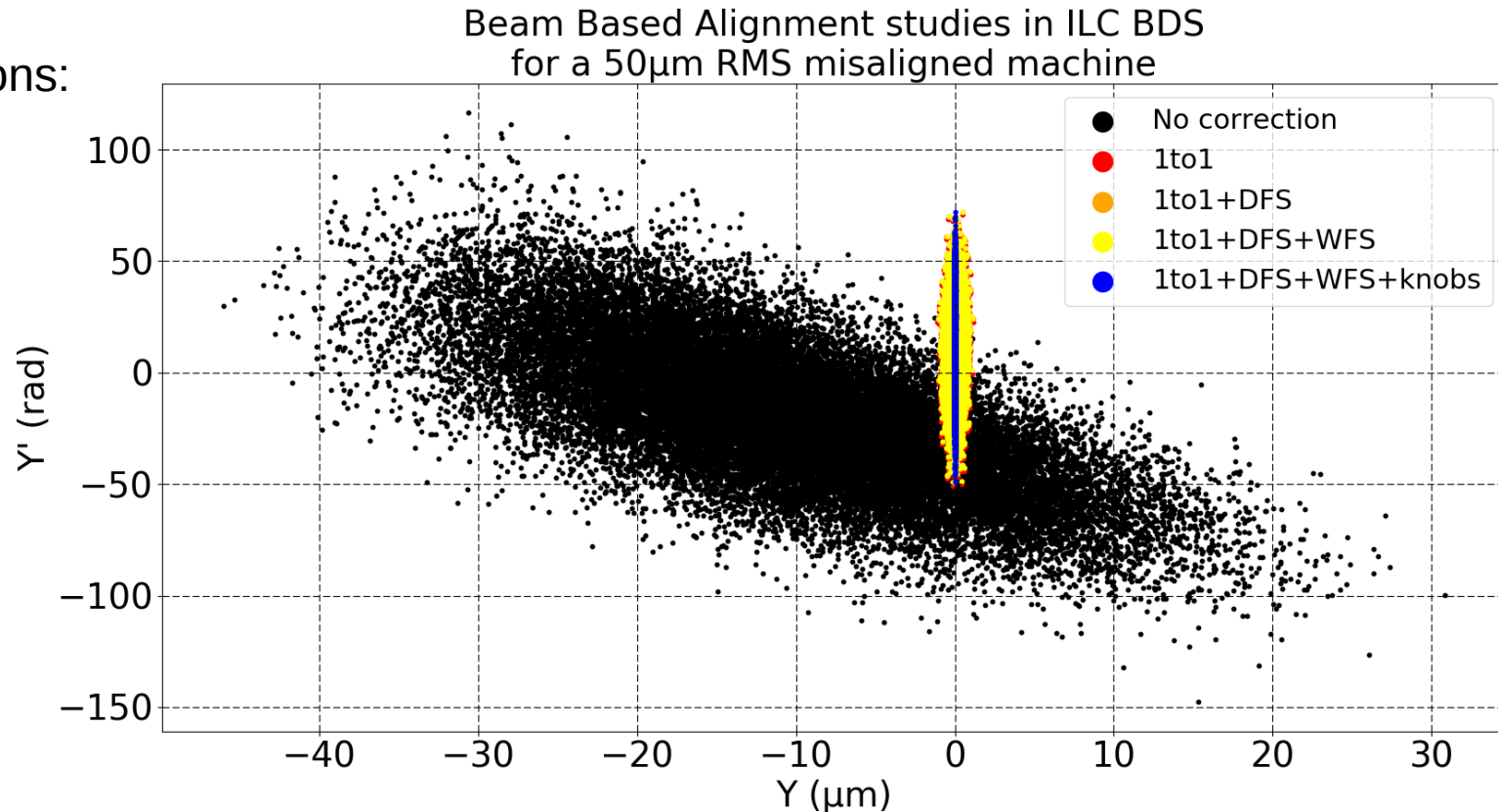


This wake potential is used at every Cavity BPM in the BDS.

+ Resistive walls calculated earlier.

Results of Beam Based Alignment + knobs in ILC BDS for one machine

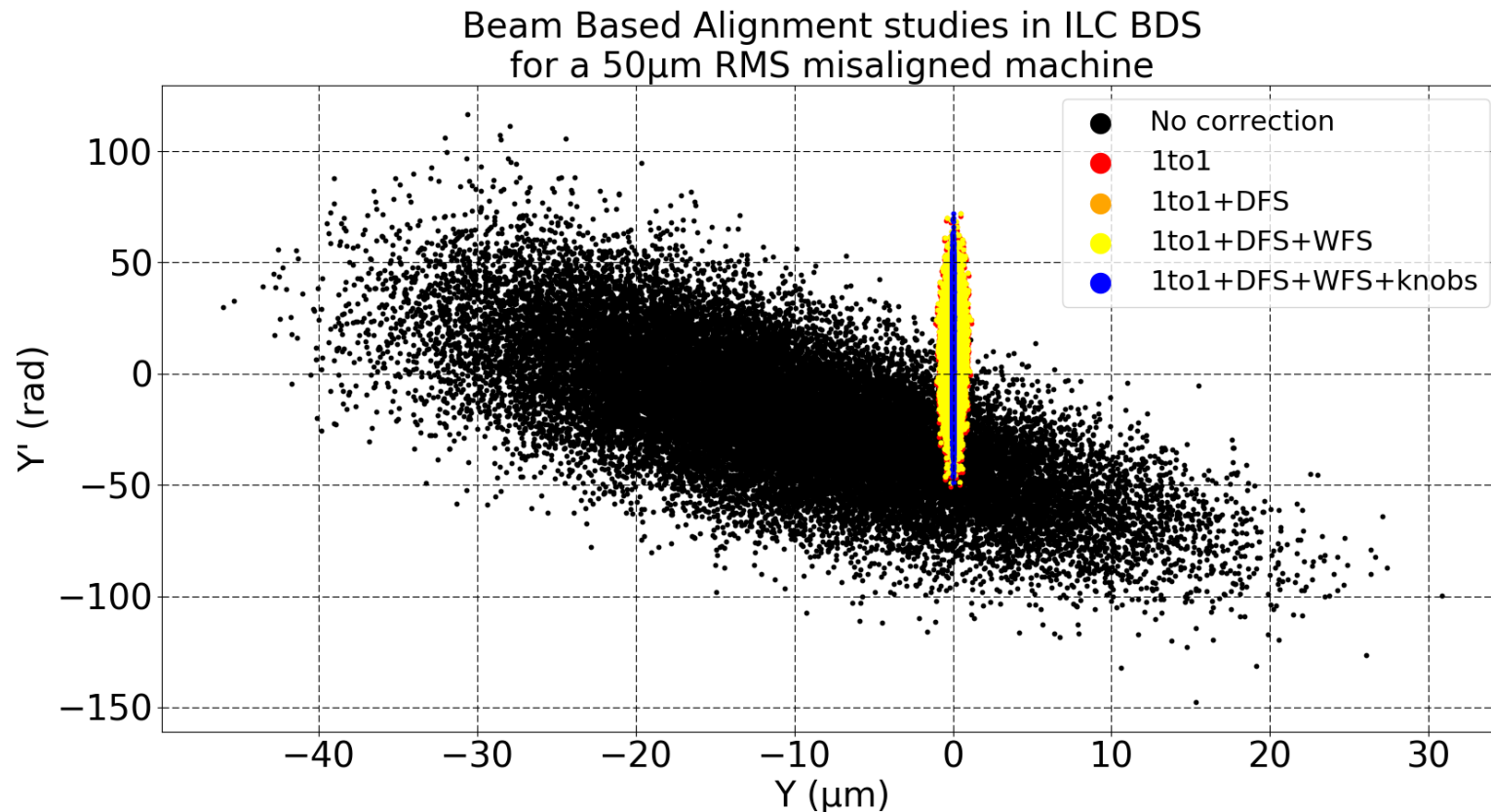
IP distributions:



Vertical beam size at IP σ_y^*

No correction	10400 nm
1to1	280 nm
1to1 + DFS	272 nm
1to1 + DFS + WFS	268 nm
1to1 + DFS + WFS + knobs	7.05 nm

Results of Beam Based Alignment + knobs in ILC BDS for one machine



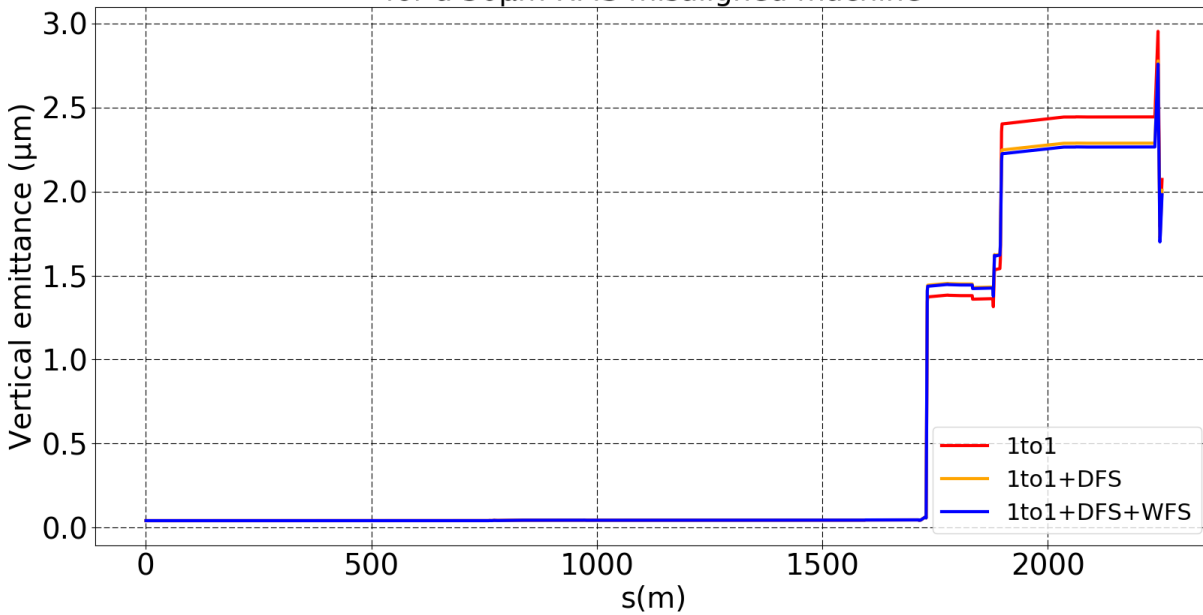
Vertical beam size at IP σ_y^*

No correction	10400 nm
1to1	280 nm
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1to1 + DFS + WFS	268 nm
1to1 + DFS + WFS + knobs	7.05 nm

The correction manages to squeeze the beam from 10 μ m to 7nm.

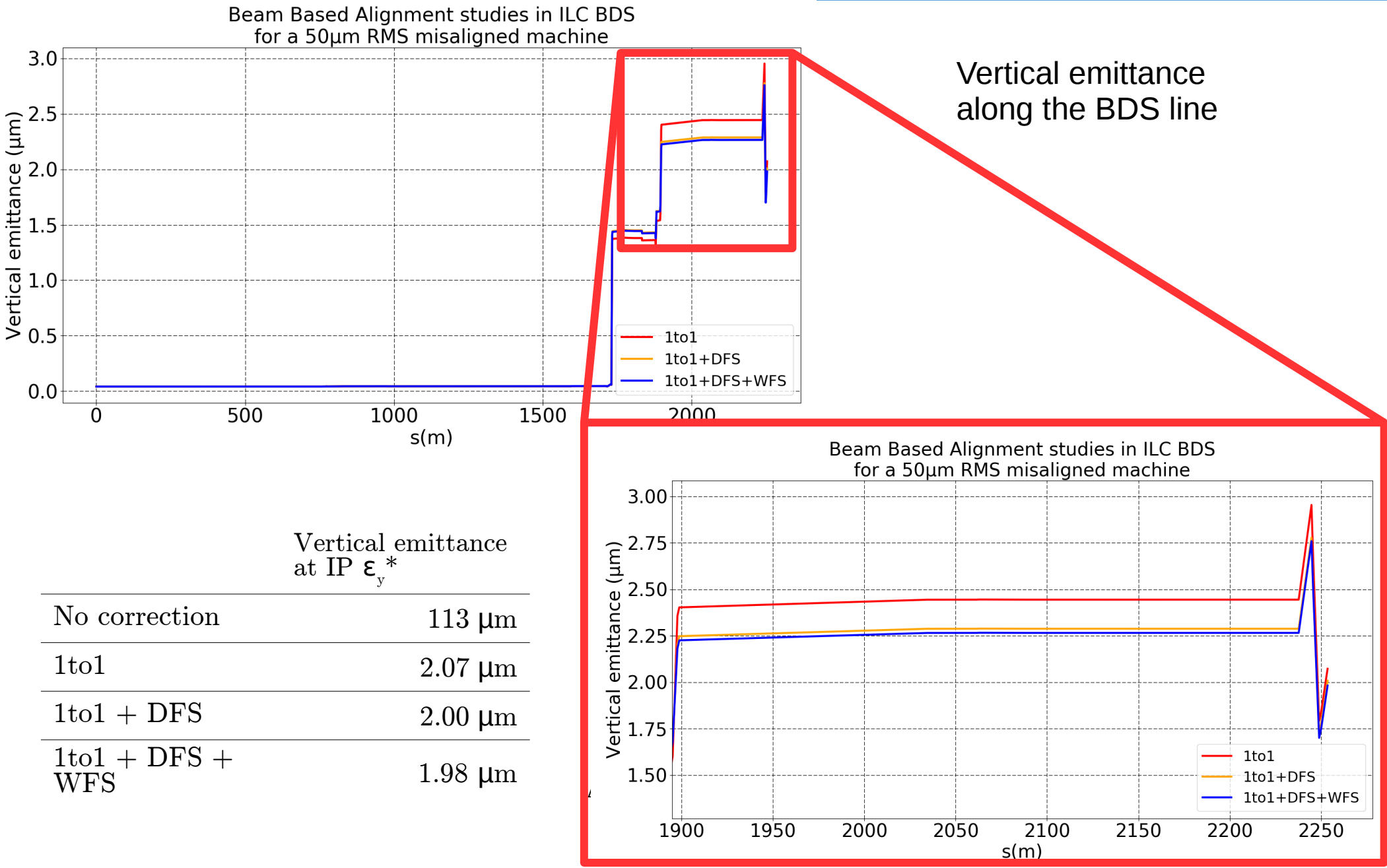
Results of Beam Based Alignment in ILC BDS for one machine

Beam Based Alignment studies in ILC BDS
for a 50 μ m RMS misaligned machine



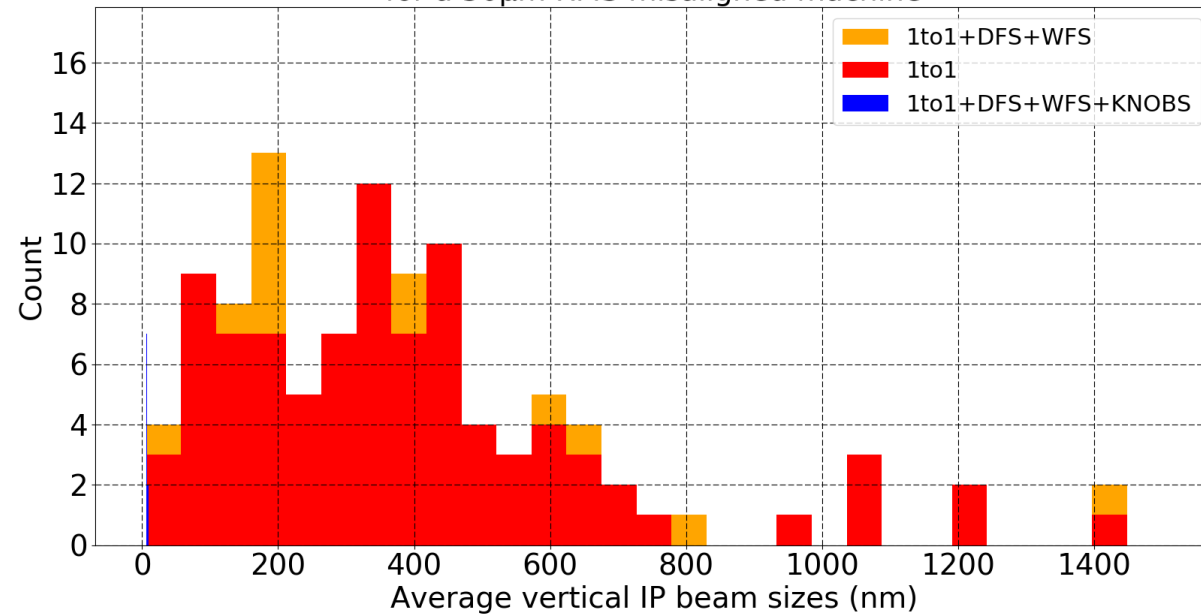
Vertical emittance
along the BDS line

Results of Beam Based Alignment in ILC BDS for one machine



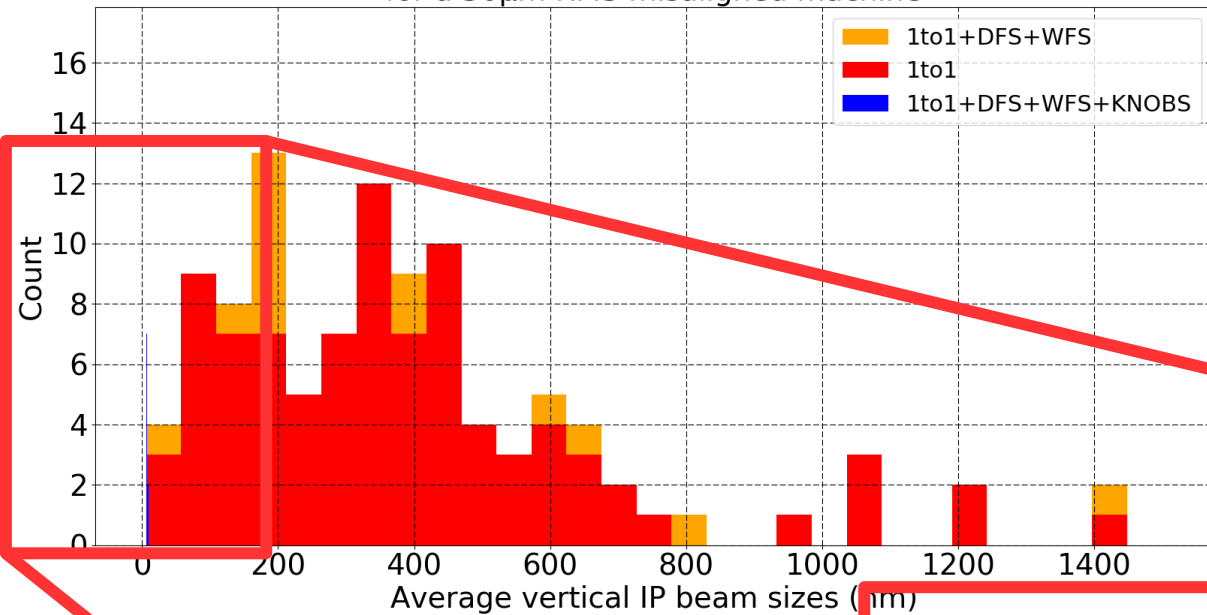
Results of Beam Based Alignment in ILC BDS for 100 machines

Beam Based Alignment studies in ILC BDS
for a 50 μ m RMS misaligned machine



Results of Beam Based Alignment in ILC BDS for 100 machines

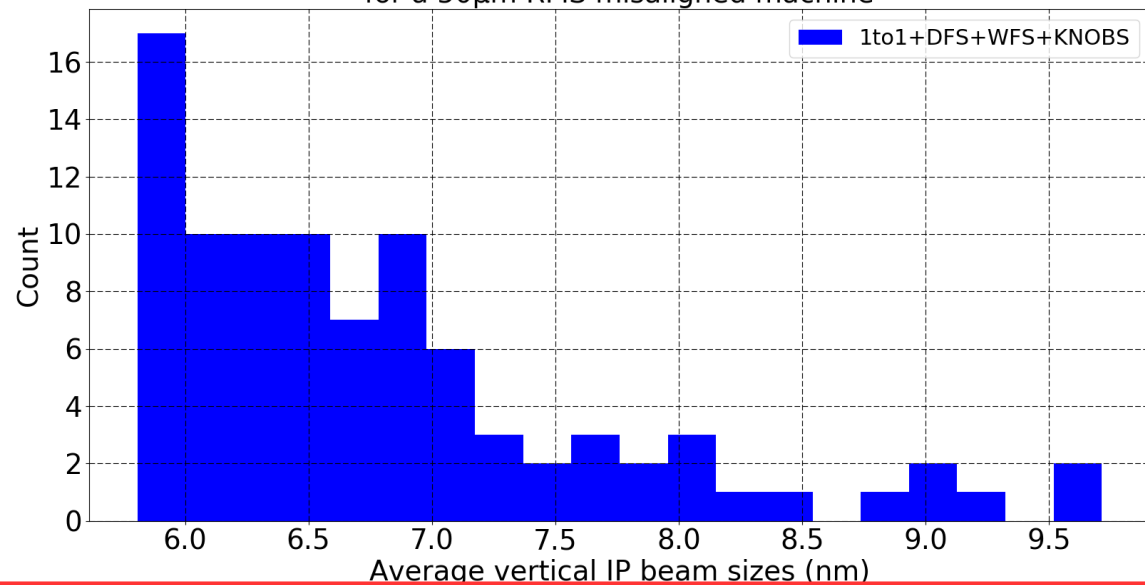
Beam Based Alignment studies in ILC BDS
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Average beam size
at IP σ_y^*

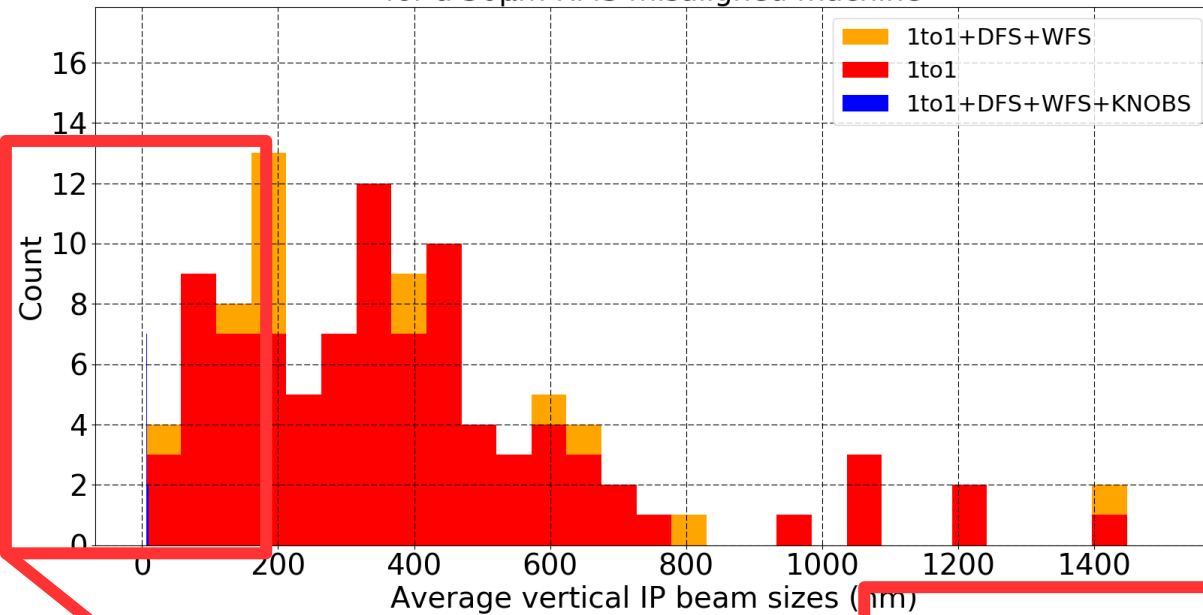
1to1	458nm
1to1 + DFS	367nm
1to1 + DFS + WFS	365nm
1to1 + DFS + WFS + KNOBS	6.8nm

Beam Based Alignment studies in ILC BDS
for a 50 μ m RMS misaligned machine



Results of Beam Based Alignment in ILC BDS for 100 machines

Beam Based Alignment studies in ILC BDS
for a 50 μ m RMS misaligned machine

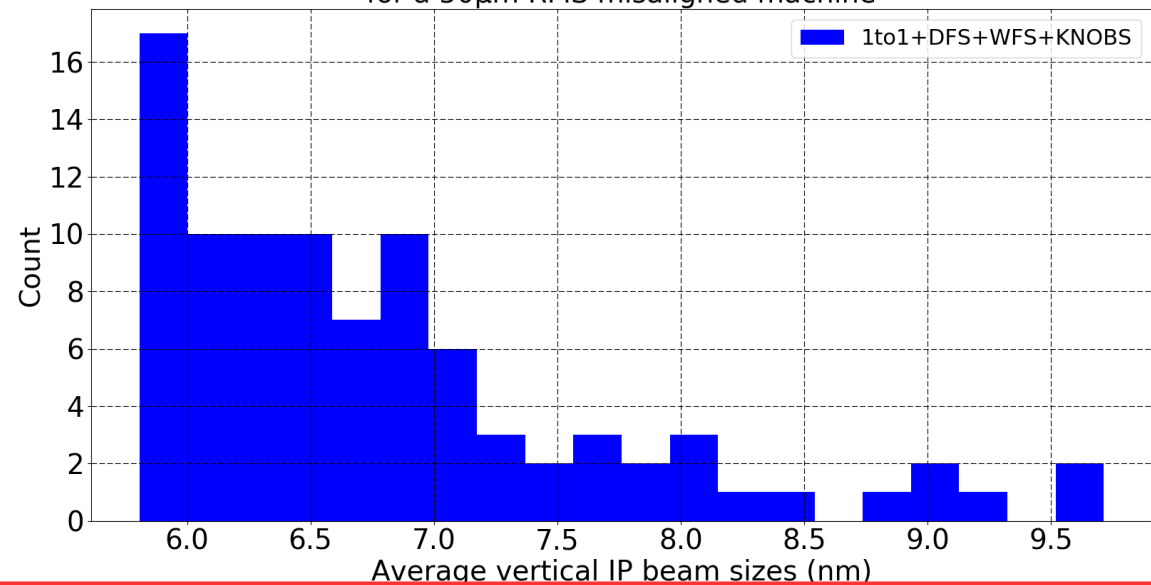


Average beam size
at IP σ_y^*

1to1	458nm
1to1 + DFS	367nm
1to1 + DFS + WFS	365nm
1to1 + DFS + WFS + KNOBS	6.8nm

The correction is significantly decreasing the beam size!

Beam Based Alignment studies in ILC BDS
for a 50 μ m RMS misaligned machine



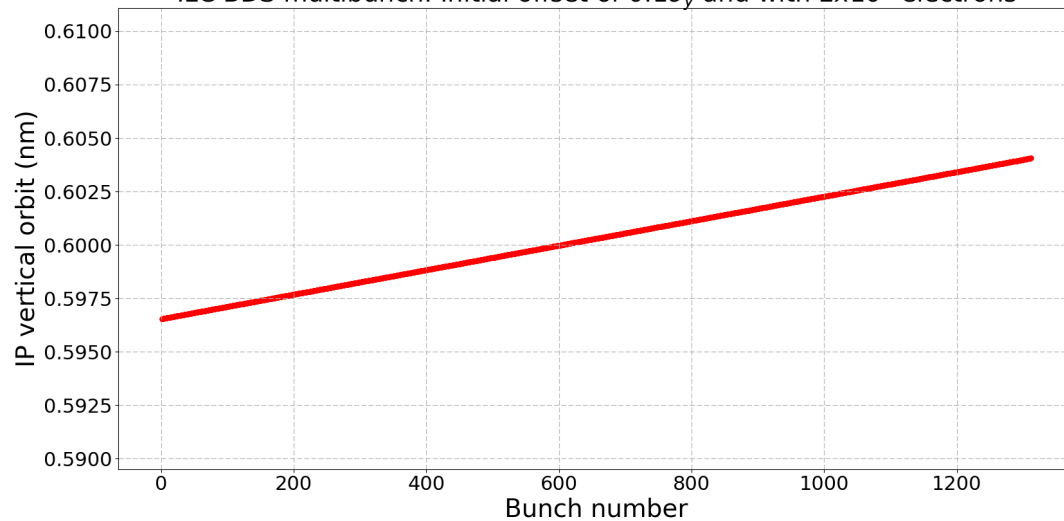
Intensity dependent effects in the BDS for a bunch train

Multi bunch simulations in ILC BDS

Orbit studies – Effect of the initial position offset

In order to study the impact of the long range wakefield with Placet, one considers each bunch to be one macro particle. 1312 consecutive macroparticles are tracked through the BDS. They are all injected with the same initial offset and one studies the vertical orbit at the IP.

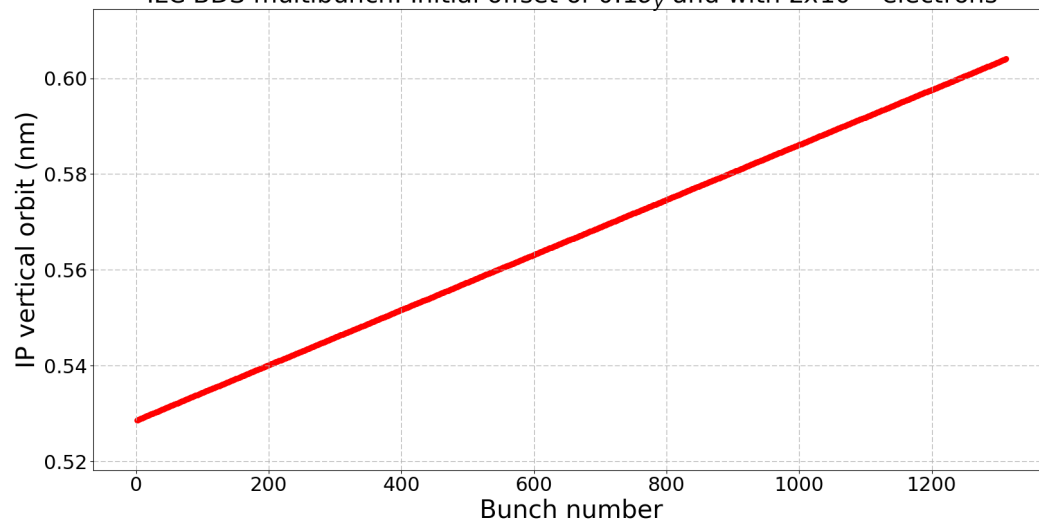
ILC BDS multibunch. Initial offset of $0.1\sigma_y$ and with 2×10^9 electrons



Here is show the IP vertical orbit at the IP with an initial position offset of $0.1\sigma_y$ at low and at high charge.

The impact of this initial vertical position offset is negligible at low charge.

ILC BDS multibunch. Initial offset of $0.1\sigma_y$ and with 2×10^{10} electrons

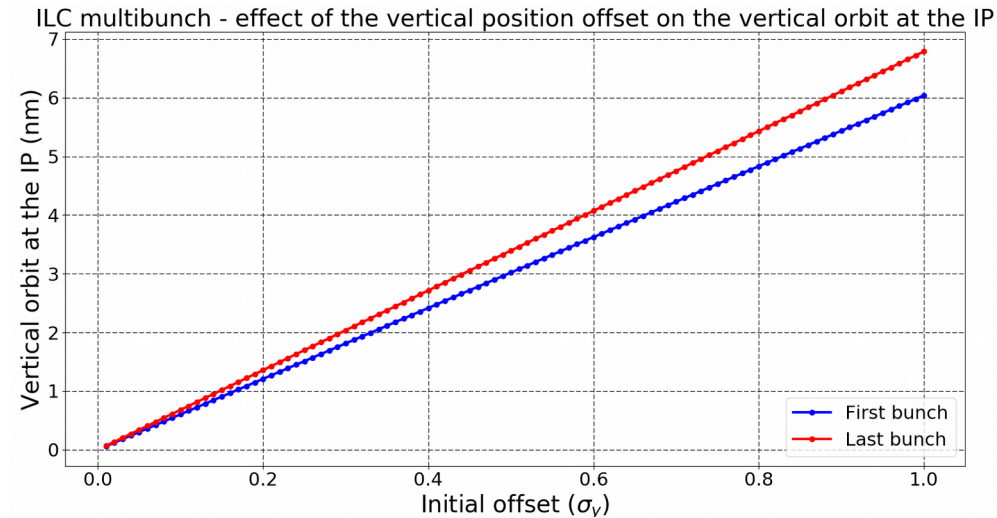


At high charge, with an initial vertical offset of $0.1\sigma_y$ the last bunch is deflected by 0.075nm compared to the first one, which corresponds to 1.32% of the vertical IP beam size (5.7nm).

Multi bunch simulations in ILC BDS

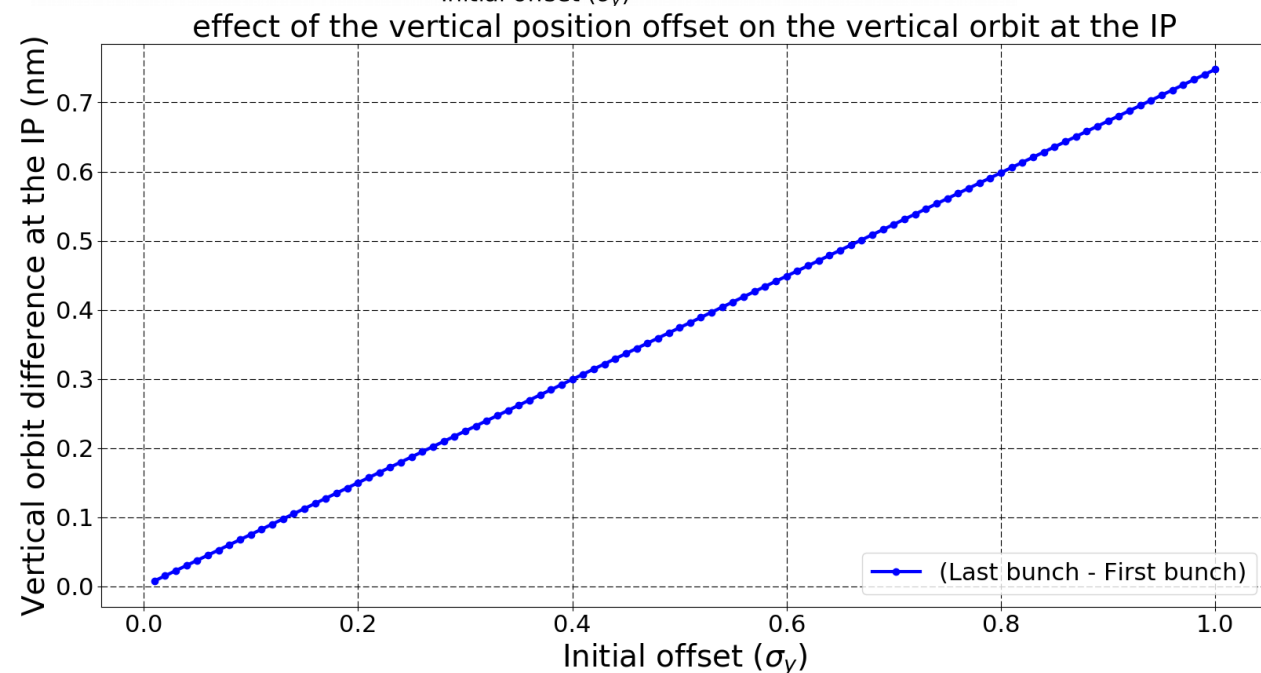
Orbit studies – Effect of the initial position offset

The same simulations were done for initial offsets between 0 and $1.0\sigma_y$ at $N=2.0 \times 10^{10}$



The impact of an initial vertical position offset on the vertical orbit at the IP is summarized in the following table:

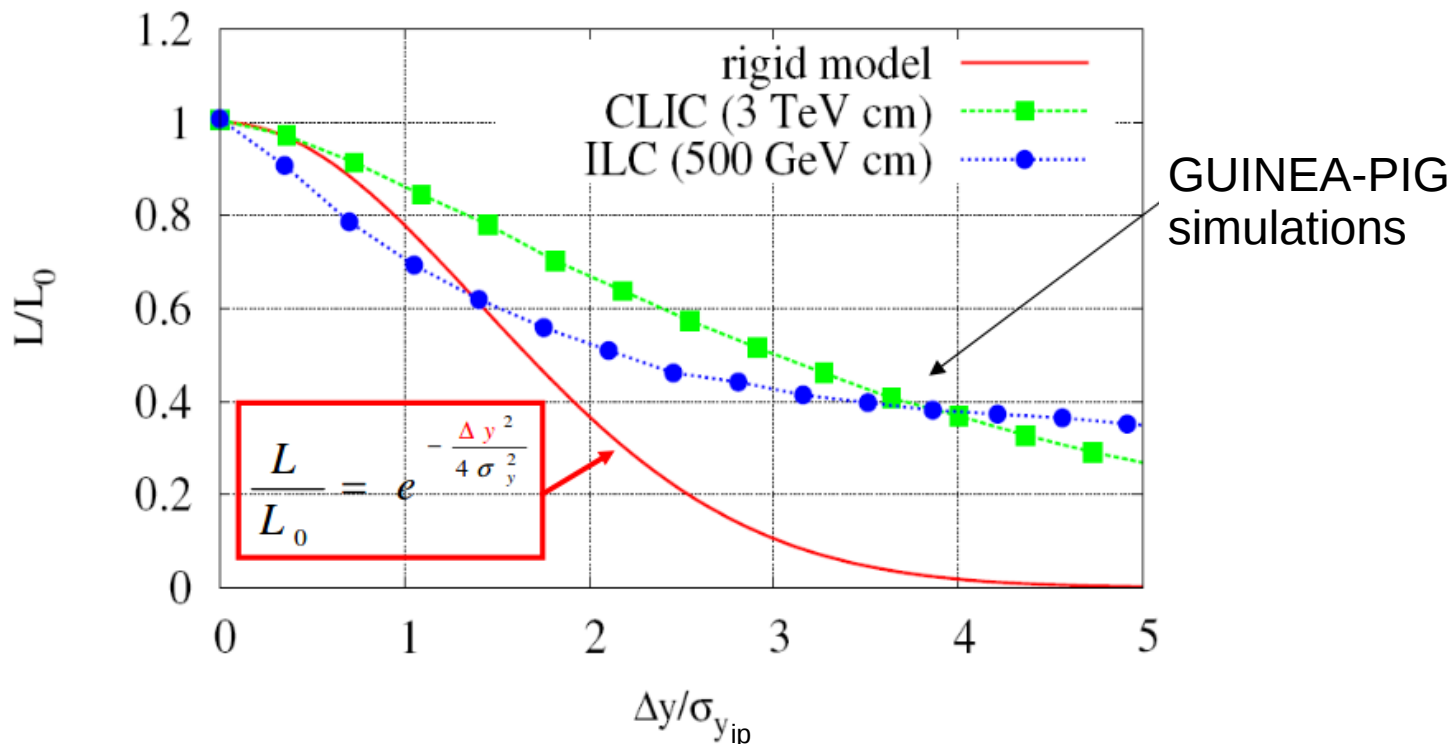
Initial vertical position offset	Vertical orbit offset at the IP
$0.1\sigma_y$	0.075nm
$0.2\sigma_y$	0.150nm
$0.3\sigma_y$	0.225nm
$0.4\sigma_y$	0.300nm
$0.5\sigma_y$	0.375nm
$0.6\sigma_y$	0.450nm
$0.7\sigma_y$	0.525nm
$0.8\sigma_y$	0.600nm
$0.9\sigma_y$	0.675nm
$1.0\sigma_y$	0.750nm



Multi bunch simulations in ILC BDS

Impact of initial position offset in the luminosity

The impact of the vertical offset at the IP on the luminosity has been simulated by Javier Resta Lopez:



Initial vertical position offset	Vertical orbit offset at the IP	$\Delta y/\sigma_{y\text{ ip}}$	L/L_0
$0.1\sigma_y$	0.075nm	0.01	0.998
$0.5\sigma_y$	0.375nm	0.07	0.986
$1.0\sigma_y$	0.750nm	0.13	0.974

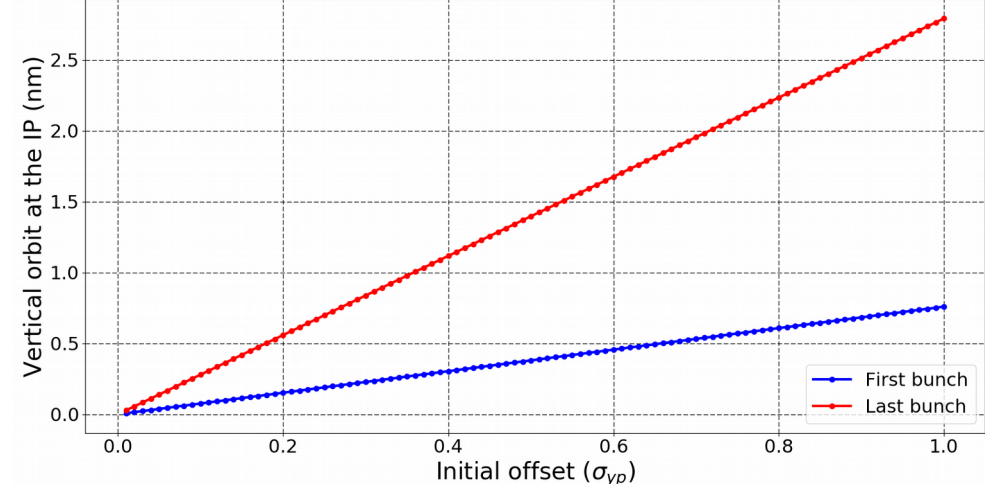
Losing 2.6% of luminosity at $N=2.0 \times 10^{10}$ with an initial position offset of $1.0\sigma_y$

Multi bunch simulations in ILC BDS

Orbit studies – Effect of the initial angle offset

The same simulations were done for initial offsets between 0 and $1.0\sigma_{yp}$ at $N=2.0 \times 10^{10}$

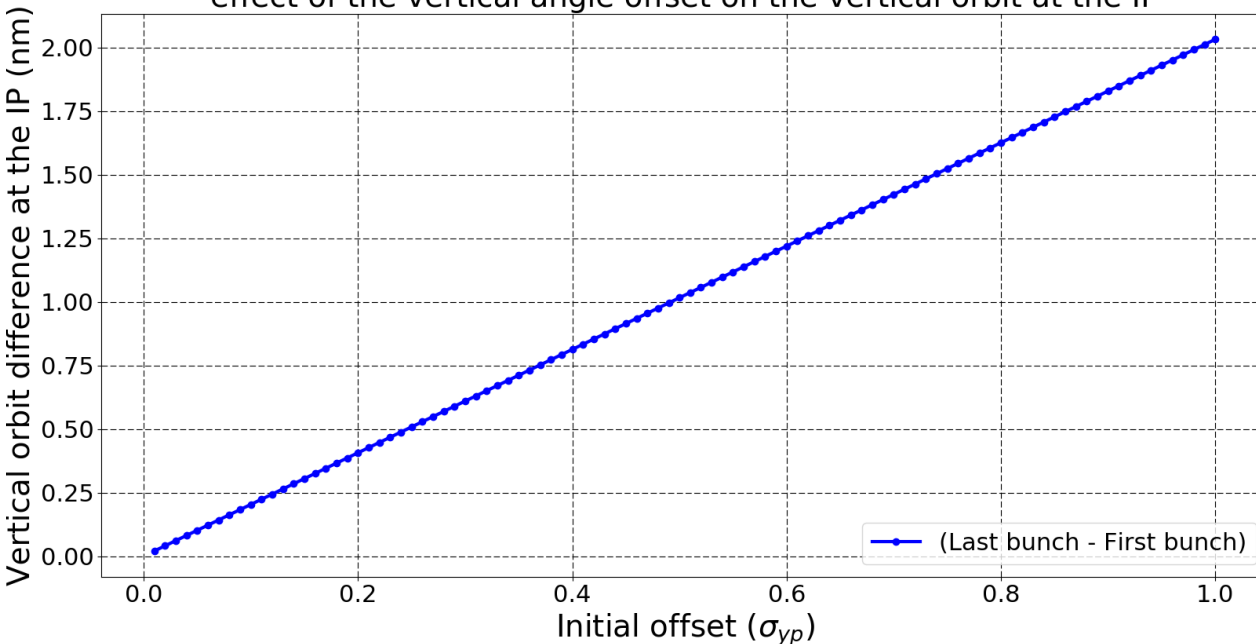
ILC multibunch - effect of the vertical angle offset on the vertical orbit at the IP



The impact of an initial angle vertical offset on the vertical orbit at the IP is summarized in the following table:

Initial vertical angle offset	Vertical orbit offset at the IP
$0.1\sigma_{yp}$	0.20nm
$0.2\sigma_{yp}$	0.41nm
$0.3\sigma_{yp}$	0.61nm
$0.4\sigma_{yp}$	0.81nm
$0.5\sigma_{yp}$	1.01nm
$0.6\sigma_{yp}$	1.22nm
$0.7\sigma_{yp}$	1.42nm
$0.8\sigma_{yp}$	1.63nm
$0.9\sigma_{yp}$	1.83nm
$1.0\sigma_{yp}$	2.03nm

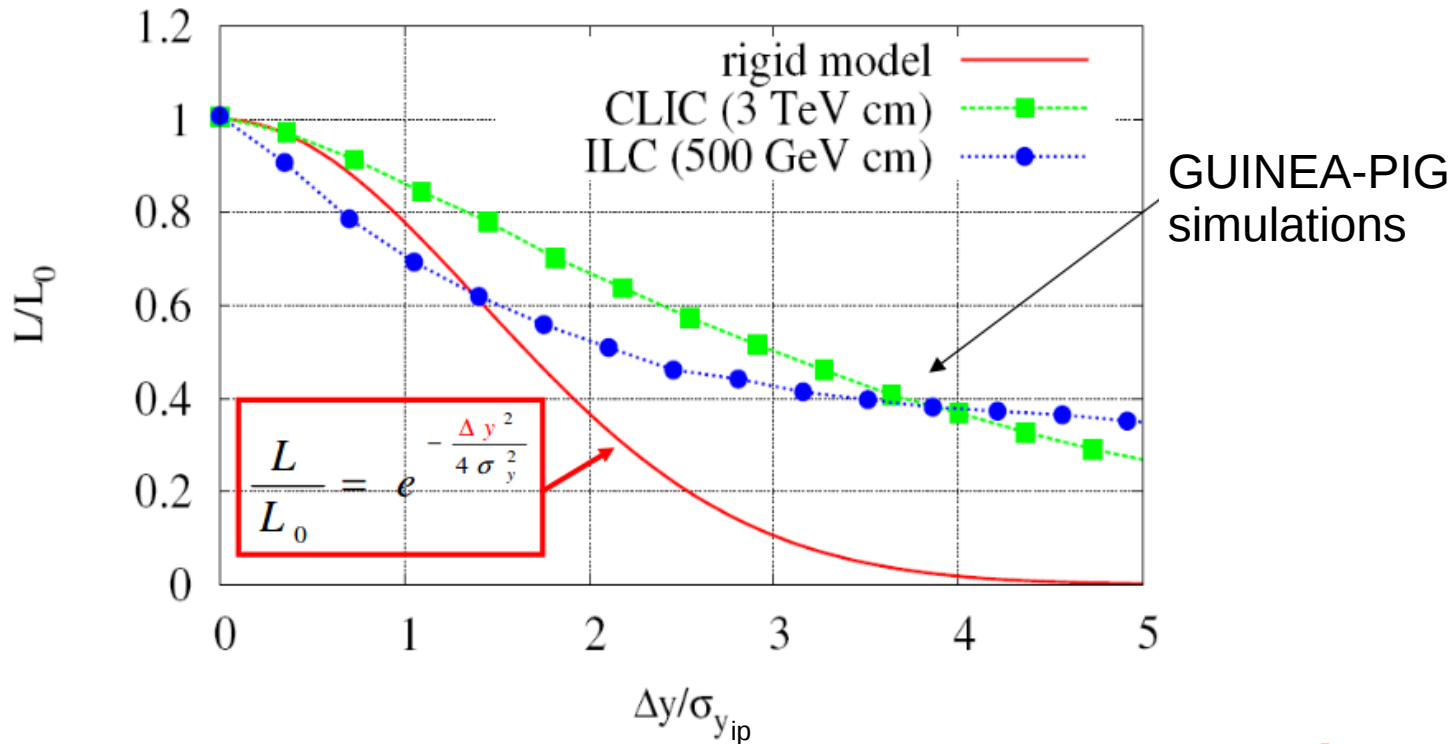
effect of the vertical angle offset on the vertical orbit at the IP



Multi bunch simulations in ILC BDS

Impact of initial angle offset in the luminosity

The impact of the vertical offset at the IP on the luminosity has been simulated by Javier Resta Lopez:



Initial vertical angle offset	Vertical orbit offset at the IP	$\Delta y / \sigma_{y \text{ ip}}$	L / L_0
$0.1\sigma_y$	0.20nm	0.04	0.992
$0.5\sigma_y$	1.01nm	0.18	0.964
$1.0\sigma_y$	2.03nm	0.36	0.926

Losing 7.4% of luminosity at $N=2.0 \times 10^{10}$ with an initial angle offset of $1.0\sigma_{yp}$

Conclusion and outlook

- **The Beam Based Alignment in the ILC BDS shows good results taking into account different types of errors.**
- **The implementation of resistive walls in Placet shows that an initial offset has a significant impact on the vertical orbit at the IP and thus on the luminosity.**

Outlooks:

- **Studying the multi bunch intensity effects using full distributions of particles.**
- **Studying the impact of the incoming jitter.**

Thank you